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Microbeam analysis — Scanning electron microscopy — Guidelines for calibrating image magnification

*Analyse par microfaisceaux — Microscopie électronique à balayage —
Lignes directrices pour l'étalonnage du grossissement d'image*



Reference number
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Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Image magnification	3
4.1 Scale marker.....	3
4.2 Expressing magnification	3
5 Reference material	4
5.1 General	4
5.2 Requirements for CRM	4
5.3 Pitch patterns on CRM.....	4
5.4 Storage and handling	4
6 Calibration procedures	5
6.1 General	5
6.2 Mounting CRM	5
6.3 Setting SEM operation conditions for calibration	5
6.4 Image recording	6
6.5 Measurement of image	6
6.6 Calibration of magnification and scale marker	7
7 Accuracy of image magnification and scale marker	8
8 Calibration report	9
8.1 General	9
8.2 Contents of calibration report.....	9
Annex A (informative) Reference materials for magnification	10
Annex B (informative) Parameters that influence the resultant magnification of an SEM	12
Annex C (informative) Uncertainties in magnification measurements	14
Annex D (informative) Example of a test report	15

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Foreword

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ISO 16700 was prepared by Technical Committee ISO/TC 202, *Microbeam analysis*, Subcommittee SC 4, *Scanning electron microscopy*.

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Introduction

The scanning electron microscope is widely used to investigate the surface structure of a range of important materials such as semiconductors, metals, polymers, glass, food and biological materials and this International Standard is relevant to the need for magnification calibration of the images. It describes the requirements for calibration of the image magnification in the scanning electron microscope using a reference material or a certified reference material.